L Number	Hits	Search Text	DB	Time stamp
-	5078	(two or dual or auxiliary or second) adj4 (ELECTRON ADJ beam$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 15:41
-	223	(two or dual or auxiliary or second) adj4 (ELECTRON ADJ beam$1) AND SECOND ADJ5 ENERGY	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/11/22 18:33
-	3750	(electron adj beam) and imag$3 and (secondary adj electron$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:53
-	2	6038018.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 08:43
-	2	6172363.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 13:41
-	103	electron adj image near3 detector	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 14:00
-	4448	250/310 and excess adj3 charge or charge adj (buildup or acculumation) or charge adj3 neutraliz$4	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 16:51

	#	Search Query	Databases	Date/Time
-	114	(250/310 and excess adj3 charge or charge adj (buildup or acculumation) or charge adj3 neutraliz$4) and (electron adj beam) and imag$3 and (secondary adj electron$1)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/01 16:53
-	2	4996434.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 13:11
-	2	5051585.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 13:11
-	0	sem and energy adj filter and band-pass	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 15:43
-	96	sem and band-pass	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 14:49
-	40	sem and band-pass and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 14:50
-	4	sem and band-pass and image near5 subtract$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 14:53
-	159	sem and image near5 subtract$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 14:54

	Query	Databases	Date/Time
73	sem and threshold and image near5 subtract$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 15:52
4	"6583413"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 15:52
3	"6583414"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 18:36
0	"6583414".pn. and low near5 energy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/02 18:36
2	6583414.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 11:17
73	(excess adj3 charge or charge adj (buildup or acculumation) or charge adj3 neutraliz$4) and electron adj beam and inspect$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:29
30	250/310 and (excess adj3 charge or charge adj (buildup or acculumation) or charge adj3 neutraliz$4) and ("low energy" or LEEM)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:07
4	(two or dual or auxiliary or second) adj4 (source or beam$1) and parallel adj imaging adj system	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:16

33	electron adj beam and inspect$3 and charge adj neutraliz$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:24
2	6172363.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:24
1225	(electron adj beam) and imag$3 and (secondary adj electron$1) and via	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 13:53
48	(electron adj beam) and imag$3 and (secondary adj electron$1) and via and neutralize	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:55
14376	(electron adj beam) and energy and via	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:17
0	sem and (seccondary adj electron near3 filter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:18
21	sem and (secondary adj electron near3 filter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:26
21	sem and (secondary adj electron near3 filter)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:33

26	leybourne.xa.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:39
401	(semiconductor or wafer) and via near3 inspect$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:40
59	((semiconductor or wafer) and via near3 inspect$3) and electron adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/03 14:40
0	sem and energy adj filter and band adj -pass	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:25
5	"5097127"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:15
20	"4896036"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:16
0	"4896036" and (excess adj3 charge or charge adj (buildup or acculumation) or charge adj3 neutraliz$4) and electron adj beam and inspect$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:30
5	"5097127"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:31

25	"3896308"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:39
17	"4896045"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:39
593	250/$.ccls. and sem and (height or depth)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:57
238	250/$.ccls. and sem and (height or depth) and charge	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 17:39
18	250/$.ccls. and sem and (height or depth) and charge adj3 (neutralization control buildup)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 16:59
51	250/$.ccls. and sem and (aspect adj ratio) and charge	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/08 17:40
4	250/$.ccls. and sem and (aspect adj ratio) and charge adj3 (neutralization control buildup)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 11:34
9	250/$.ccls. and sem and (photons or photo adj electrons) and charge adj3 (neutralization control buildup)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 11:56

14	250/$.ccls. and peem	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 11:56
411	electron adj beam and photon adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:26
4	(electron adj beam and photon adj beam) and energy adj filter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:27
737	photoelectron and surface near4 charg$3	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:29
164	photoelectron and surface near4 charg$3 and electron adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:38
58	photoelectron and surface adj charg$3 and electron adj beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/10 15:38
2	5493116.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 11:48
2	6232787.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 13:19

0	08/892,734.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 13:20
0	08892734.pn.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:03
2	photo-emission adj (electron adj microscope)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:09
18	photo-emission and (electron adj microscope)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:23
116	("Photo Emission Electron Microscope") or (PEEM)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:24
11	(("Photo Emission Electron Microscope") or (PEEM)) and filter	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:32
41	(("Photo Emission Electron Microscope") or (PEEM)) and energy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 14:32
8	electron near threshold adj energy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 15:50

-	1059	(bandpass or band-pass pr band adj pass) near4 energy	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:12
-	33	((bandpass or band-pass pr band adj pass) near4 energy) and secondary adj electron$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:03
-	13	((bandpass or band-pass pr band adj pass) near4 energy) and secondary adj electron$1 and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:10
-	66062	energy near4 (first or second)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:11
-	13276	energy near4 (first or second) and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:11
-	104	(bandpass or band-pass pr band adj pass) near4 energy and energy near4 (first or second) and image	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/11 16:12